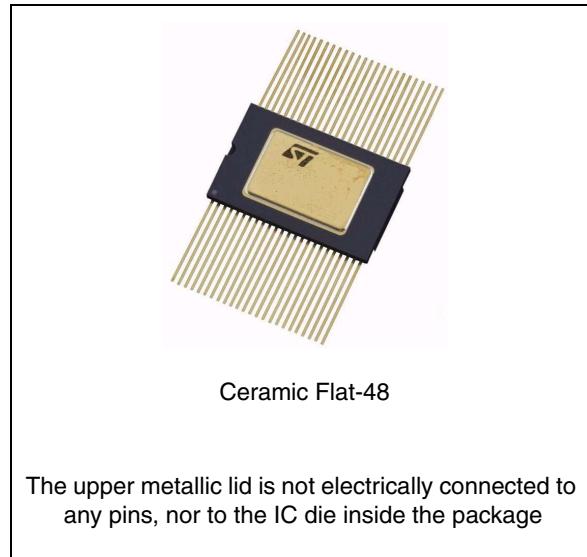


## Rad-hard 16-bit transceiver, 3.3 V to 5 V bidirectional level shifter

Datasheet – production data

## Features

- Fully compatible with 54ACS164245
- Dual supply bidirectional level shifter
- Extended voltage range from 2.3 V to 5.5 V
- Separated enable pin for 3-state output
- Schmidt-triggered I/Os: 100 mV hysteresis
- Internal 26 Ω limiting resistor on each I/O
- High speed:  $T_{pd} = 8$  ns maximum
- Bus hold
- Fail safe
- Cold spare
- Hermetic package
- 100 krad (Si) at any Mil1019 dose rate
- SEL immune to 110MeV.cm<sup>2</sup>/mg LET ions
- RHA QML-V qualified



## Description

The 54AC164245 is a rad-hard advanced high-speed CMOS, Schmitt trigger 16-bit bidirectional multi-purpose transceiver with 3-state outputs and cold sparing.

Designed for use as an interface between a 5 V bus and a 3.3 V bus in mixed 5 V/3.3 V supply systems, it achieves high-speed operation while maintaining the CMOS low-power dissipation.

All pins have cold spare buffers to change them to high impedance when  $V_{DD}$  is tied to ground.

This IC is intended for two-way asynchronous communication between the data buses and the direction of the data transmission is determined by the nDIR inputs.

The A port interfaces with the 3.3 V bus but can also operate at 2.3 V. The B port operates with the 5 V bus.

**Table 1. Device summary**

| Reference       | SMD pin         | Quality level     | Package | Lead finish | Mass   | EPPL   | Temp range        |
|-----------------|-----------------|-------------------|---------|-------------|--------|--------|-------------------|
| RHRAC164245K1   | -               | Engineering model | Flat-48 | Gold        | 1.50 g | -      | -55 °C to +125 °C |
| RHRAC164245K01V | 5962R9858008VYC | QMLV-Flight       |         | Gold        |        | Target |                   |

Note: Contact your ST sales office for information on the specific conditions for products in die form.

# 1 Functional description

Figure 1. Logic diagram

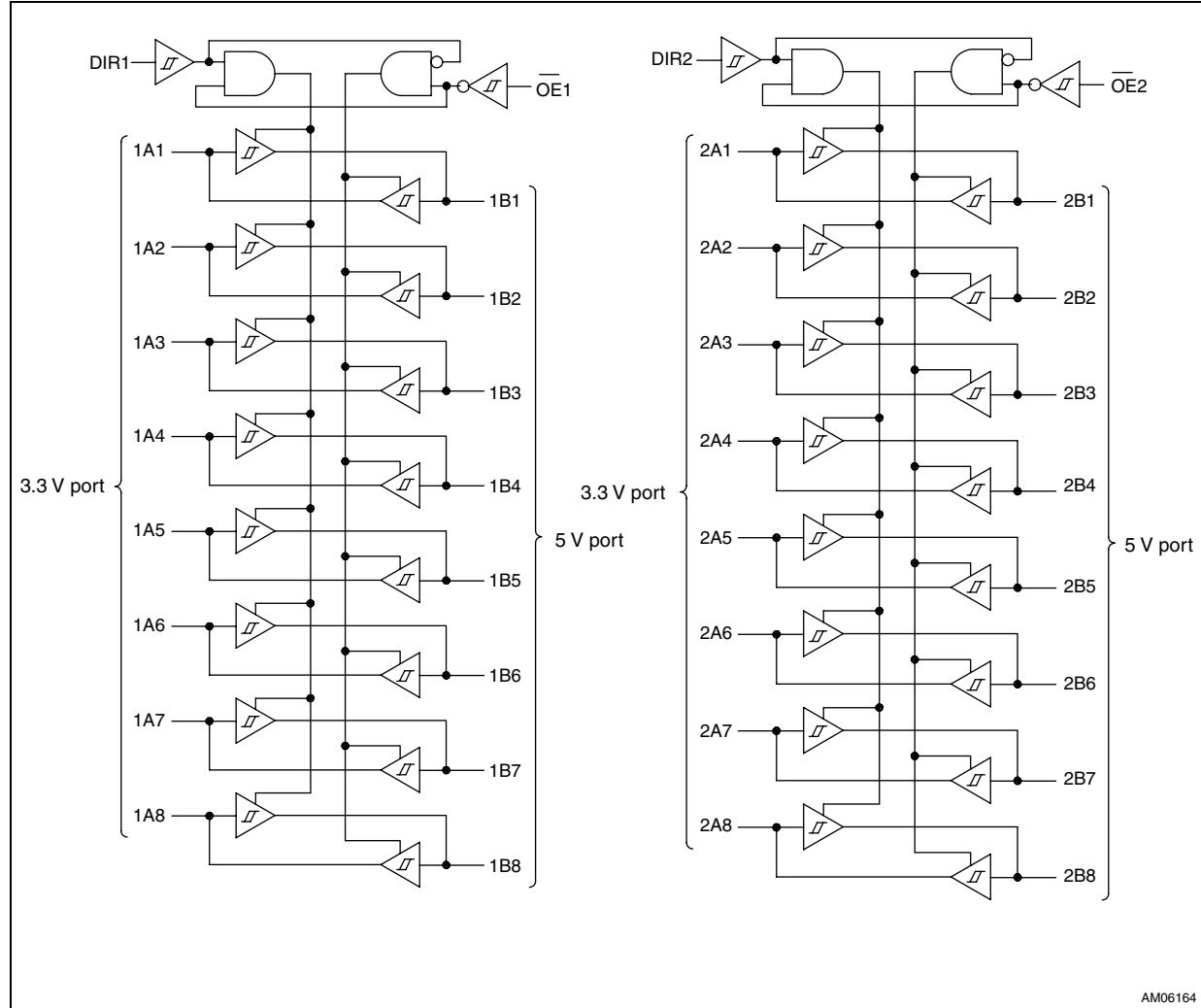


Table 2. Function table

| Enable, $\overline{OE}_x$ | Direction, $DIR_x$ | Operation       |
|---------------------------|--------------------|-----------------|
| L                         | L                  | B data to A bus |
| L                         | H                  | A data to B bus |
| H                         | X                  | Isolation       |

## 1.1 Cold spare

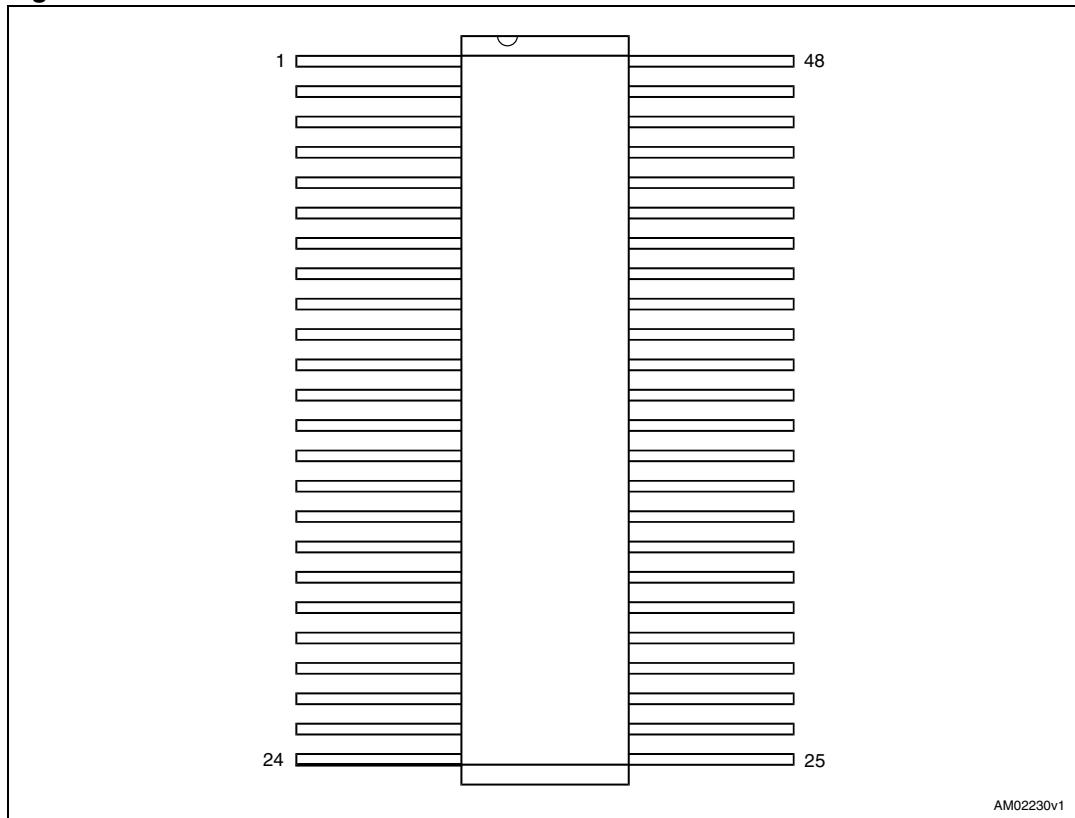
The 54AC164245 features a cold spare input and output buffers. In high reliability applications, cold sparing enables a redundant device to be tied to the data bus with its power supply at 0 V ( $V_{DD} = V_{SS}$ ,  $V_{DD} - V_{SS} = 0$  V) without affecting the bus signals or injecting current from the I/Os to the power supplies. Cold sparing also allows to keep unpowered redundant devices so that they can be switched on only when required. Power consumption is therefore reduced by switching off the redundant circuit. This has no impact on the application. Cold spare is achieved by implementing a high impedance between I/Os and  $V_{DD}$ . The ESD protection is ensured through a non-conventional dedicated structure.

## 1.2 Power-up

During power up, all outputs are forced to high impedance. The high-impedance state is maintained approximately until  $V_{DD}$  is high, thus avoiding any transient and erroneous signals during power-up.

## 1.3 Pin connections

**Figure 2. Pin connections**



AM02230v1

**Table 3. Pin descriptions**

| Pin n°                         | Symbol           | Name and function                             |
|--------------------------------|------------------|---|
| 1                              | DIR1             | Direction control inputs                      |
| 2, 3, 5, 6, 8, 9, 11, 12       | 1B1 to 1B8       | Side B inputs or 3-state outputs (5 V port)   |
| 4,10, 15, 21, 28, 34, 39, 45   | V <sub>SS</sub>  | Reference voltage to ground                   |
| 7, 18                          | V <sub>DD1</sub> | Supply voltage (5 V)                          |
| 13, 14, 16, 17, 19, 20, 22, 23 | 2B1 to 2B8       | Side B inputs or 3-state outputs (5 V port)   |
| 24                             | DIR2             | Direction control inputs                      |
| 25                             | nG2              | Output enable inputs (active low)             |
| 31, 42                         | V <sub>DD2</sub> | Supply voltage (3.3 V)                        |
| 47, 46, 44, 43, 41, 40, 38, 37 | 1A1 to 1A8       | Side A inputs or 3-state outputs (3.3 V port) |
| 36, 35, 33, 32, 30, 29, 27, 26 | 2A1 to 2A8       | Side A inputs or 3-state outputs (3.3 V port) |
| 48                             | nG1              | Output enable inputs (active low)             |

## 2 Absolute maximum ratings and operating conditions

Absolute maximum ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

**Table 4. Absolute maximum ratings (1) (2) (3)**

| Symbol     | Parameter  | Value                   | Unit |
|------------|--|-------------------------|------|
| $V_{DD1}$  | 5 V supply voltage <sup>(4)</sup>  | -0.3 to +6.0            | V    |
| $V_{DD2}$  | 3 V supply voltage   | -0.3 to +6.0            | V    |
| $V_{IA}$   | DC input voltage range port A  | -0.3 to $V_{DD1}+0.3$ V | V    |
| $V_{IB}$   | DC input voltage range port B  | -0.3 to $V_{DD1}+0.3$ V | V    |
| $V_{OA}$   | DC output voltage range port A   | -0.3 to $V_{DD1}+0.3$ V | V    |
| $V_{OB}$   | DC output voltage range port B   | -0.3 to $V_{DD1}+0.3$ V | V    |
| $I_{IA}$   | DC input currents port A, anyone input   | $\pm 10$                | mA   |
| $I_{IB}$   | DC input currents port B, anyone input   | $\pm 10$                | mA   |
| $T_{stg}$  | Storage temperature range  | -65 to +150             | °C   |
| $T_L$      | Lead temperature (10 sec)  | 300                     | °C   |
| $T_J$      | Junction temperature range   | 175                     | °C   |
| $R_{thja}$ | Thermal resistance junction to ambient <sup>(5)</sup><br>Flat package, 48 pins | TBD                     | °C/W |
| $R_{thjc}$ | Thermal resistance junction to case <sup>(5)</sup><br>Flat package, 48 pins    | TBD                     | °C/W |
| ESD        | HBM: human body model <sup>(6)</sup>   | 2                       | kV   |

1. Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
2. Unless otherwise noted, all voltages are referenced to  $V_{SS}$ .
3. The limits for the parameters specified herein shall apply over the full specified  $V_{DD}$  range and case temperature range of -55°C to +125°C.
4.  $V_{DD1}$  (5 V) may remain disconnected.
5. Short-circuits can cause excessive heating and destructive dissipation. Values are typical.
6. Human body model: a 100 pF capacitor is charged to the specified voltage, then discharged through a 1.5 kΩ resistor between two pins of the device. This is done for all couples of connected pin combinations while the other pins are floating.

**Table 5. Operating conditions<sup>(1)</sup>**

| Symbol      | Parameter  | Value                    | Unit   |
|-------------|--|--------------------------|--------|
| $V_{DD1}$   | Supply voltage   | 4.5 to 5.5 or 2.3 to 3.6 | V      |
| $V_{DD2}$   | Supply voltage   | 2.3 to 3.6 or 4.5 to 5.5 | V      |
| $V_I$       | Input voltage  | 0 to $V_{DD1}$           | V      |
| $V_O$       | Output voltage   | 0 to $V_{DD1}$           | V      |
| $T_{op}$    | Operating temperature  | -55 to +125              | °C     |
| $d_t / d_v$ | Input rise and fall time $V_{CC} = 3.0, 4.5$ or $5.5$ <sup>(2)</sup> | 0 to 8                   | ns / V |

1. Unless otherwise noted, all voltages are referenced to  $V_{SS}$ .

2. Derate system propagation delays by difference in rise time to switch point for  $t_r$  or  $t_f > 1$  ns/V.

### 3 Electrical characteristics

$T_{op} = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{DD1} = 4.5 \text{ V}$  to  $5.5 \text{ V}$ ,  $V_{DD2} = 2.7 \text{ V}$  to  $3.6 \text{ V}$ , unless otherwise specified.

**Table 6. DC specifications (1)**

| Symbol   | Parameter   | Port voltage | Test condition ( $V_{DD}$ ) (2)  | Limits |               | Unit          |
|----------|---|--------------|--|--------|---------------|---------------|
|          |   |              |  | Min.   | Max.          |               |
| $V_{T+}$ | Schmitt trigger positive going threshold port A   | 3.3 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.7 $V_{DD2}$ | V             |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ and } 5.5 \text{ V}$ |        | 0.7 $V_{DD2}$ |               |
|          | Schmitt trigger positive going threshold port B   | 3.3 V        | $V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$<br>$V_{DD1} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.7 $V_{DD1}$ |               |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.7 $V_{DD1}$ |               |
| $V_{T-}$ | Schmitt trigger positive going threshold port A   | 3.3 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.3 $V_{DD2}$ | V             |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ and } 5.5 \text{ V}$ |        | 0.3 $V_{DD2}$ |               |
|          | Schmitt trigger positive going threshold port B   | 3.3 V        | $V_{DD1} = 2.7 \text{ and } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.3 $V_{DD1}$ |               |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ |        | 0.3 $V_{DD1}$ |               |
| $V_H$    | Schmitt trigger range of hysteresis port A  | 3.3 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ | 0.4    |               | V             |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ and } 5.5 \text{ V}$ | 0.6    |               |               |
|          | Schmitt trigger range of hysteresis port B  | 3.3 V        | $V_{DD1} = 2.7 \text{ and } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ | 0.4    |               |               |
|          |   | 5.0 V        | $V_{DD1} = 4.5 \text{ and } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ and } 3.6 \text{ V}$ | 0.6    |               |               |
| $I_{IH}$ | Input current high port A (for input under test $V_I = V_{DD2}$ other inputs, $V_I = V_{DD1}$ or $V_{SS}$ ) | 3.3 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                   |        | 3             | $\mu\text{A}$ |
|          |   | 5.0 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$                                   |        | 3             |               |
|          | Input current high port B (for input under test $V_I = V_{DD1}$ other inputs, $V_I = V_{DD2}$ or $V_{SS}$ ) | 3.3 V        | $V_{DD1} = 3.6 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                   |        | 3             |               |
|          |   | 5.0 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                   |        | 3             |               |

**Table 6. DC specifications (1) (continued)**

| Symbol    | Parameter  | Port voltage | Test condition ( $V_{DD}$ ) <sup>(2)</sup>             | Limits |      | Unit          |
|-----------|--|--------------|--|--------|------|---------------|
|           |  |              |  | Min.   | Max. |               |
| $I_{IL}$  | Input current low port A (for input under test $V_I = V_{SS}$ other inputs, $V_I = V_{DD1}$ or $V_{SS}$ )                              | 3.3 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$ | -1     |      | $\mu\text{A}$ |
|           |  | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$ | -1     |      |               |
|           | Input current low port B (for input under test $V_I = V_{SS}$ other inputs, $V_I = V_{DD1}$ or $V_{SS}$ )                              | 3.3 V        | $V_{DD1} = 3.6 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$ | -1     |      |               |
|           |  | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$ | -1     |      |               |
| $I_{CS}$  | Input current cold spare mode port A = port B = 5.5 V = $V_I$<br>DIRn = 5.5 V, OEn = 5.5 V   |              | $V_{DD1} = 0 \text{ V}$                                | -1     | 5    | $\mu\text{A}$ |
|           | Input current cold spare mode port A = port B = 5.5 V = $V_I$<br>DIRn = 0 V, OEn = 5.5 V   |              | $V_{DD1} = 0 \text{ V}$                                | -1     | 5    |               |
|           | Input current cold spare mode port A = port B = 5.5 V = $V_I$<br>DIRn = 5.5 V, OEn = 0 V   |              | $V_{DD1} = 0 \text{ V}$                                | -1     | 5    |               |
|           | Input current cold spare mode port A = port B = 5.5 V = $V_I$<br>DIRn = 0 V, OEn = 0 V   |              | $V_{DD1} = 0 \text{ V}$                                | -1     | 5    |               |
| $V_{OL1}$ | Low level output voltage<br>Port A, $I_{OL} = 8 \text{ mA}$ for all inputs affecting output under test,<br>$V_I = V_{DD2}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.5  | $\text{V}$    |
|           |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$ |        | 0.4  |               |
|           | Low level output voltage<br>Port B, $I_{OL} = 8 \text{ mA}$ for all inputs affecting output under test,<br>$V_I = V_{DD1}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.5  |               |
|           |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.4  |               |
| $V_{OL2}$ | Low level output voltage   | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.2  | $\text{V}$    |
|           | Port A, $I_{OL} = 100 \mu\text{A}$ for all inputs affecting output under test, $V_I = V_{DD2}$ or $V_{SS}$                             | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$ |        | 0.2  |               |
|           | Low level output voltage   | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.2  |               |
|           | Port B, $I_{OL} = 100 \mu\text{A}$ For all inputs affecting output under test, $V_I = V_{DD1}$ or $V_{SS}$                             | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$ |        | 0.2  |               |

**Table 6. DC specifications (1) (continued)**

| Symbol         | Parameter  | Port voltage | Test condition ( $V_{DD}$ ) <sup>(2)</sup>   | Limits        |      | Unit |
|----------------|--|--------------|--|---------------|------|------|
|                |  |              |  | Min.          | Max. |      |
| $V_{OH1}$      | High level output voltage port A,<br>$I_{OH} = -8 \text{ mA}$ for all inputs<br>affecting output under test,<br>$V_I = V_{DD2}$ or $V_{SS}$    | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD2}-0.9$ |      | V    |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$                             | $V_{DD2}-0.7$ |      |      |
|                | High level output voltage port B,<br>$I_{OH} = -8 \text{ mA}$ for all inputs<br>affecting output under test,<br>$V_I = V_{DD1}$ or $V_{SS}$    | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD1}-0.9$ |      |      |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD1}-0.7$ |      |      |
| $V_{OH2}$      | High level output voltage<br>port A, $I_{OH} = -100 \mu\text{A}$ for all<br>inputs affecting output under<br>test, $V_I = V_{DD2}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD2}-0.2$ |      | V    |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$                             | $V_{DD2}-0.2$ |      |      |
|                | High level output voltage<br>port B, $I_{OH} = -100 \mu\text{A}$ for all<br>inputs affecting output under<br>test, $V_I = V_{DD1}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD1}-0.2$ |      |      |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$                             | $V_{DD1}-0.2$ |      |      |
| $I_{OL}^{(3)}$ | Output current (sink)<br>port A, $V_I = V_{SS}$  | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OL} = 0.5 \text{ V}$ | 8.0           |      | mA   |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$<br>$V_{OL} = 0.4 \text{ V}$ | 8.0           |      |      |
|                | Output current (sink)<br>port B, $V_I = V_{SS}$  | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OL} = 0.5 \text{ V}$ | 8.0           |      |      |
|                |  | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OL} = 0.4 \text{ V}$ | 8.0           |      |      |

**Table 6. DC specifications (1) (continued)**

| Symbol            | Parameter   | Port voltage | Test condition ( $V_{DD}$ ) <sup>(2)</sup>   | Limits |      | Unit          |
|-------------------|---|--------------|--|--------|------|---------------|
|                   |   |              |  | Min.   | Max. |               |
| $I_{OH}^{(4)}$    | Output current (source) port A,<br>$V_I = V_{DD2}$ or $V_{SS}$  | 3.3 V        | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OH} = V_{DD2} - 0.9 \text{ V}$ | -8.0   |      | mA            |
|                   |   | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ V}$<br>$V_{OH} = V_{DD2} - 0.7 \text{ V}$ | -8.0   |      |               |
|                   | Output current (source) port B,<br>$V_I = V_{DD2}$ or $V_{SS}$  | 3.3 V        | $V_{DD1} = 2.7 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OH} = V_{DD2} - 0.9 \text{ V}$ | -8.0   |      |               |
|                   |   | 5 V          | $V_{DD1} = 4.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ V}$<br>$V_{OH} = V_{DD2} - 0.7 \text{ V}$ | -8.0   |      |               |
| $I_{OZH}$         | Three-state output leakage current high port A, for input under test, $V_I = V_{DD2}$ other inputs, $V_O = V_{DD2}$ $V_I = V_{DD2}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       |        | 3.0  | $\mu\text{A}$ |
|                   |   |              | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$                                       |        | 3.0  |               |
|                   | Three-state output leakage current high port B, for input under test, $V_I = V_{DD1}$ other inputs, $V_O = V_{DD1}$ $V_I = V_{DD1}$ or $V_{SS}$ | 3.3 V        | $V_{DD1} = 3.6 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       |        | 3.0  |               |
|                   |   | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       |        | 3.0  |               |
| $I_{OZL}$         | Three-state output leakage current low port A, for input under test, $V_I = V_{SS}$ other inputs, $V_O = V_{SS}$ $V_I = V_{DD2}$ or $V_{SS}$    | 3.3 V        | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       | -1.0   |      | $\mu\text{A}$ |
|                   |   | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$                                       | -1.0   |      |               |
|                   | Three-state output leakage current low port B, for input under test, $V_I = V_{SS}$ other inputs, $V_O = V_{SS}$ $V_I = V_{DD1}$ or $V_{SS}$    | 3.3 V        | $V_{DD1} = 3.6 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       | -1.0   |      |               |
|                   |   | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 3.6 \text{ V}$                                       | -1.0   |      |               |
| $I_{OS}^{(3)(4)}$ | Short circuit output current port A, $V_O = V_{DD2}$ or $V_{SS}$  | 3.3 V        | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$       | -100   | 100  | mA            |
|                   |   | 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$       | -200   | 200  |               |
|                   | Short circuit output current port B, $V_O = V_{DD1}$ or $V_{SS}$  | 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$       | -100   | 100  |               |
|                   |   | 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$       | -200   | 200  |               |

**Table 6. DC specifications (1) (continued)**

| Symbol               | Parameter  | Port voltage | Test condition ( $V_{DD}$ ) <sup>(2)</sup>  | Limits |      | Unit          |
|----------------------|--|--------------|---|--------|------|---------------|
|                      |  |              |   | Min.   | Max. |               |
| $P_D$ (3) (5)<br>(6) | Power dissipation, port A,<br>$C_L = 50 \text{ pF}$ per switching output | 3.3 V        | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$            |        | 1.5  | mW/<br>MHz    |
|                      |  | 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$            |        | 2.0  |               |
|                      | Power dissipation, port B,<br>$C_L = 50 \text{ pF}$ per switching output | 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$            |        | 1.5  |               |
|                      |  | 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$            |        | 2.0  |               |
| $I_{DDQ}$            | Quiescent supply current port<br>A, $V_I = V_{DD2}$ or $V_{SS}$          | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$<br>at $25^\circ\text{C}$                   |        | 10   | $\mu\text{A}$ |
|                      |  |              | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$<br>at $-55 \text{ to } +125^\circ\text{C}$ |        | 100  |               |
|                      | Quiescent supply current port<br>B, $V_I = V_{DD1}$ or $V_{SS}$          | 5 V          | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$<br>at $25^\circ\text{C}$                   |        | 10   |               |
|                      |  |              | $V_{DD1} = 5.5 \text{ V}$<br>$V_{DD2} = 5.5 \text{ V}$<br>at $-55 \text{ to } +125^\circ\text{C}$ |        | 100  |               |
| $C_I$                | Input capacitance  |              | $f = 1 \text{ MHz}$ $V_{DD1} = V_{DD2} = 0 \text{ V}$   |        | 15   | pF            |
| $C_O$                | Output capacitance   |              | $f = 1 \text{ MHz}$ $V_{DD1} = V_{DD2} = 0 \text{ V}$   |        | 15   | pF            |
| (7)                  | Functional test $V_{IH} = 0.7 V_{DD}$ ,<br>$V_{IL} = 0.3 V_{DD}$         |              | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$            | L      | H    |               |

- Each input/output, as applicable, is tested at the specified temperature, for the specified limits, to the tests specified in SMD5962-98580 table I. Non-designated output terminals are high level logic, low level logic or open, except for all  $I_{DDQ}$  tests, where the output terminals are open. When performing these tests, the current meter must be placed in the circuit such that all current flows through the meter.
- This device requires both  $V_{DD1}$  and  $V_{DD2}$  power supplies for operation. The power supply is indicated and followed by the voltage to which the power supply is set to the given test.
- This parameter is supplied as a design limit but not guaranteed or tested.
- No more than one output should be shorted at a time for a maximum duration of one second.
- Power does not include power contribution of any CMOS output sink current.
- Power dissipation specified per switching output.
- Tests must be performed in sequence, attributes data only. Functional tests shall include the truth table and other logic patterns used for fault detection. The test vectors used to verify the truth table must, at minimum, test all the functions of each input and output. All possible input to output logic patterns per function shall be guaranteed, if not tested, to the function table, [Table 2](#). Functional tests are performed in sequence as approved by the qualifying activity on qualified devices. Functional tests are conducted in accordance with MIL-STD-883 with the following input test conditions:  
 $V_{IH} = V_{IH}(\min + 20\%, -0\%)$ ;  $V_{IL} = V_{IL}(\max + 0\%, -50\%)$ , as specified herein, for TTL, CMOS, or Schmitt compatible inputs.  
Devices are guaranteed to  $V_{IH(\min)}$  and  $V_{IL(\max)}$ .

**Table 7.** AC electrical characteristics <sup>(1)</sup>

| Symbol           | Parameter   | Port voltage                   | Test condition ( $V_{DD}$ )  | Limits |      | Unit |
|------------------|---|--------------------------------|--|--------|------|------|
|                  |   |                                |  | Min.   | Max. |      |
| t <sub>PLH</sub> | Propagation delay time, data to bus (active low) $C_L = 50 \text{ pF}$                                  | Port A = 3.3 V<br>Port B = 5 V | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   | ns   |
|                  | Propagation delay time, data to bus (active low) $C_L = 50 \text{ pF}$                                  | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 15   |      |
| t <sub>PHL</sub> | Propagation delay time, data to bus (active high) $C_L = 50 \text{ pF}$                                 | Port A = 3.3V<br>Port B = 5 V  | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   | ns   |
|                  | Propagation delay time, data to bus (active high) $C_L = 50 \text{ pF}$                                 | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 15   |      |
| t <sub>PZL</sub> | Propagation delay time, output enable, $\overline{OEn}$ to bus (active low), $C_L = 50 \text{ pF}$      | Port A = 3.3 V<br>Port B = 5V  | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 18   | ns   |
|                  | Propagation delay time, output enable, $\overline{OEn}$ to bus (active low), $C_L = 50 \text{ pF}$      | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 18   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 12   |      |
| t <sub>PZH</sub> | Propagation delay time, output enable, $\overline{OEn}$ to bus (active high), $C_L = 50 \text{ pF}$     | Port A = 3.3 V<br>Port B = 5 V | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 18   | ns   |
|                  | Propagation delay time, output enable, $\overline{OEn}$ to bus (active high), $C_L = 50 \text{ pF}$     | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 18   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 12   |      |
| t <sub>PLZ</sub> | Propagation delay time, output disable, $\overline{OEn}$ to bus (low impedance), $C_L = 50 \text{ pF}$  | Port A = 3.3 V<br>Port B = 5 V | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   | ns   |
|                  | Propagation delay time, output disable, $\overline{OEn}$ to bus (low impedance), $C_L = 50 \text{ pF}$  | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.6 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.6 \text{ V}$ | 1.0    | 20   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 15   |      |
| t <sub>PHZ</sub> | Propagation delay time, output disable, $\overline{OEn}$ to bus (high impedance), $C_L = 50 \text{ pF}$ | Port A = 3.3 V<br>Port B = 5 V | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   | ns   |
|                  | Propagation delay time, output disable, $\overline{OEn}$ to bus (high impedance), $C_L = 50 \text{ pF}$ | Port A = Port B = 3.3 V        | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   |      |
|                  |   | Port A = Port B = 5 V          | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 12   |      |

**Table 7.** AC electrical characteristics <sup>(1)</sup> (continued)

| Symbol          | Parameter   | Port voltage                     | Test condition ( $V_{DD}$ )  | Limits |      | Unit |
|-----------------|---|----------------------------------|--|--------|------|------|
|                 |   |                                  |  | Min.   | Max. |      |
| $t_{PZL}^{(1)}$ | Propagation delay time, output enable, DIRn to bus (active low), $C_L = 50 \text{ pF}$      | Port A = 3.3 V<br>Port B = 5 V   | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   | ns   |
|                 | Propagation delay time, output enable, DIRn to bus (active low), $C_L = 50 \text{ pF}$      | Port A = Port B = 3.3 V          | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   |      |
|                 |   | Port A = Port B = 5 V            | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 12   |      |
| $t_{PZH}^{(1)}$ | Propagation delay time, output enable, DIRn to bus (active high), $C_L = 50 \text{ pF}$     | Port A = 3.3 V<br>Port B = 5 V   | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   | ns   |
|                 | Propagation delay time, output enable, DIRn to bus (active high), $C_L = 50 \text{ pF}$     | Port A = Port B = 3.3 V          | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 18   |      |
|                 |   | Port A = Port B = 5 V            | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 12   |      |
| $t_{PLZ}^{(1)}$ | Propagation delay time, output disable, DIRn to bus (low impedance), $C_L = 50 \text{ pF}$  | Port A = 3.3 V<br>Port B = 5 V   | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 20   | ns   |
|                 | Propagation delay time, output disable, DIRn to bus (low impedance), $C_L = 50 \text{ pF}$  | Port A = Port B = 3.3 V          | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 20   |      |
|                 |   | Port A = Port B = 5 V            | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 15   |      |
| $t_{PHZ}^{(1)}$ | Propagation delay time, output disable, DIRn to bus (high impedance), $C_L = 50 \text{ pF}$ | Port A = 3.3 V<br>Port B = 5.0 V | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 20   | ns   |
|                 | Propagation delay time, output disable, DIRn to bus (high impedance), $C_L = 50 \text{ pF}$ | Port A = Port B = 3.3 V          | $V_{DD1} = 2.7 \text{ to } 3.3 \text{ V}$<br>$V_{DD2} = 2.7 \text{ to } 3.3 \text{ V}$ | 1.0    | 20   |      |
|                 |   | Port A = Port B = 5 V            | $V_{DD1} = 4.5 \text{ to } 5.5 \text{ V}$<br>$V_{DD2} = 4.5 \text{ to } 5.5 \text{ V}$ | 1.0    | 15   |      |

1. Guaranteed by design but not tested.

## 4 Radiations

Total dose (Mil1019 dose rate): all parameters are post-irradiation guaranteed by wafer-lot acceptance (after dose, all guaranteed electrical parameters are tested on a sample of units of each wafer lot). All parameters provided in [Table 6](#) and [Table 7](#) apply to both pre- and post-irradiation. The 54AC164245 is a pure CMOS product. The irradiation is performed at high dose rates.

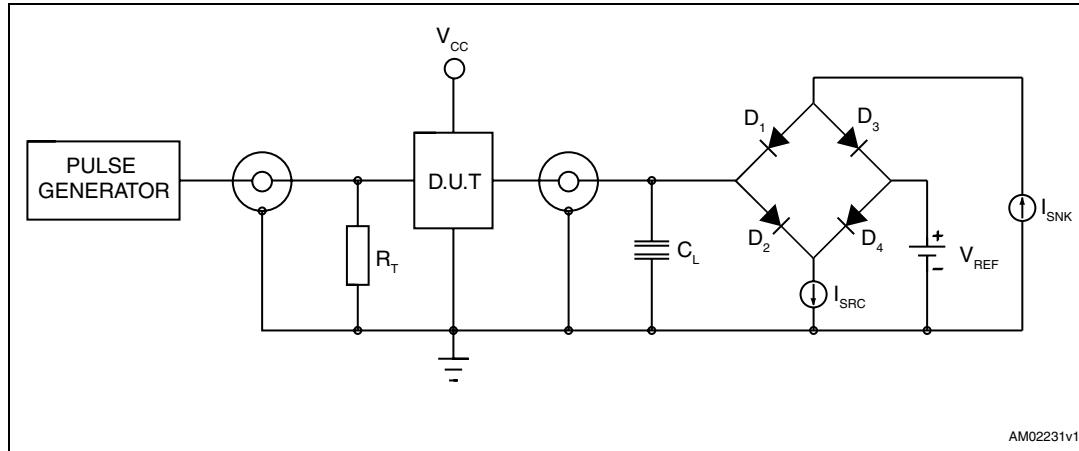
Heavy ions: the behavior of the product when submitted to heavy ions is guaranteed by qualification and is not tested in production. Heavy-ion trials are performed on qualification lots only.

**Table 8. Radiations**

| Type       | Features  | Value | Unit                    |
|------------|---|-------|-------------------------|
| TID        | Total Ionizing dose<br>High dose rate (50 - 300 rad/sec) up to: | 100   | k rad                   |
| Heavy ions | SEL immune (at 125°C) up to:                                    | 110   | MeV.cm <sup>2</sup> /mg |
|            | SEU immune up to:   | 64    |                         |

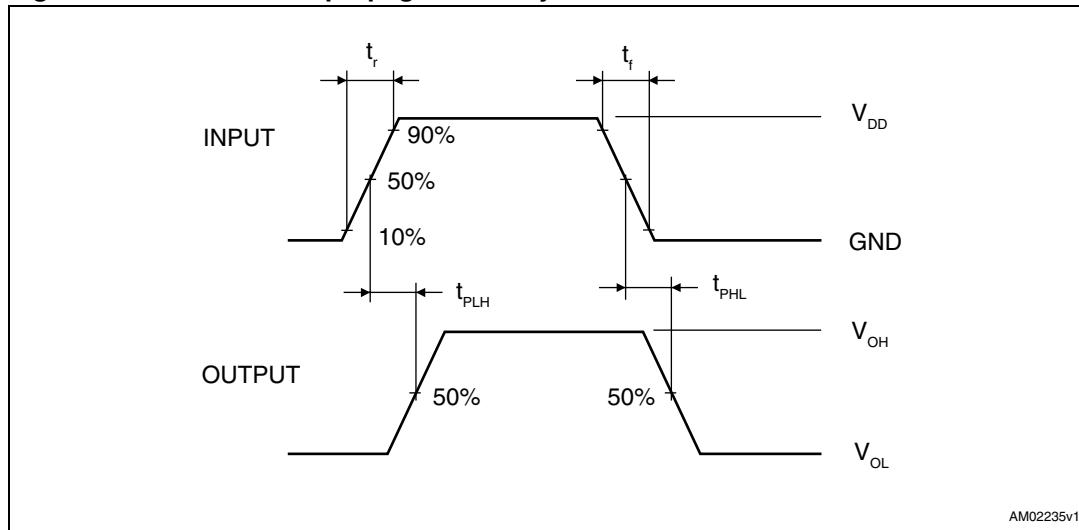
## 5 Test circuit

**Figure 3. Test circuit**



Note:  $C_L = 50 \text{ pF}$  or equivalent (includes jig and probe capacitance),  $R_T = Z_{OUT}$  of pulse generator (typically  $50\Omega$ ),  $V_{REF} = 0.5 V_{DD}$ .  $I_{SRC}$  is set to  $-1.0 \text{ mA}$  and  $I_{SNK}$  is set to  $1.0 \text{ mA}$  for  $t_{PLH}$  and  $t_{PHL}$  measurements. Input signal from pulse generator:  $V_I = 0.0 \text{ V}$  to  $V_{DD}$ ;  $f = 10 \text{ MHz}$ ;  $t_r = 1.0 \text{ V/ns}$  "0.3 V/ns";  $t_f = 1.0 \text{ V/ns}$  "0.3 V/ns";  $t_r$  and  $t_f$  are measured from  $0.1 V_{DD}$  to  $0.9 V_{DD}$  and from  $0.9 V_{DD}$  to  $0.1 V_{DD}$  respectively.

**Figure 4. Waveform 1: propagation delay**



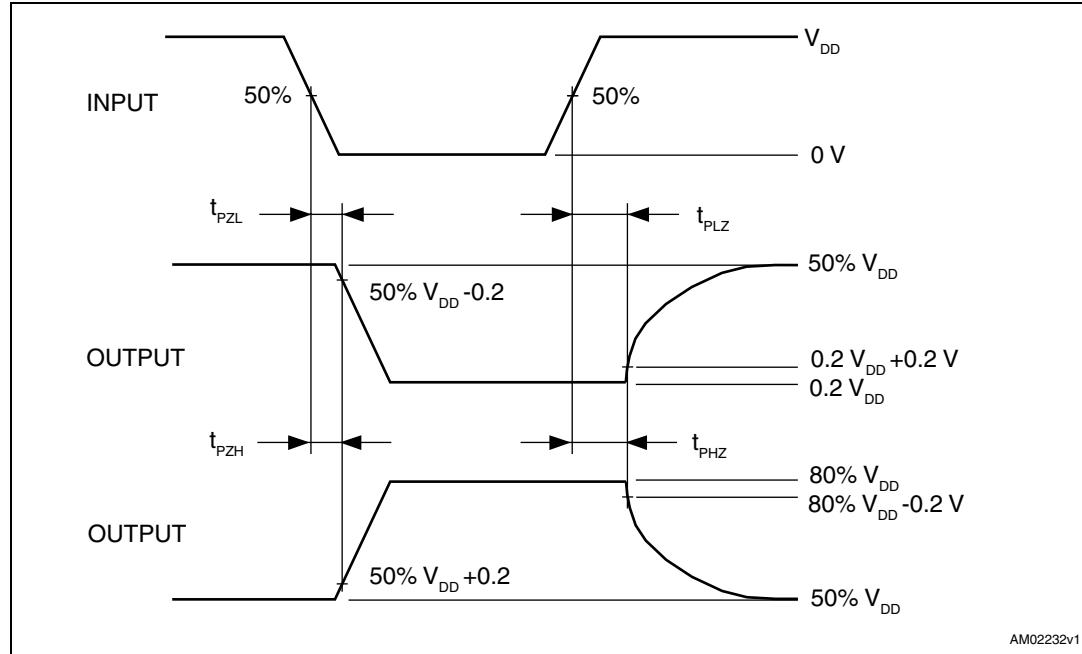
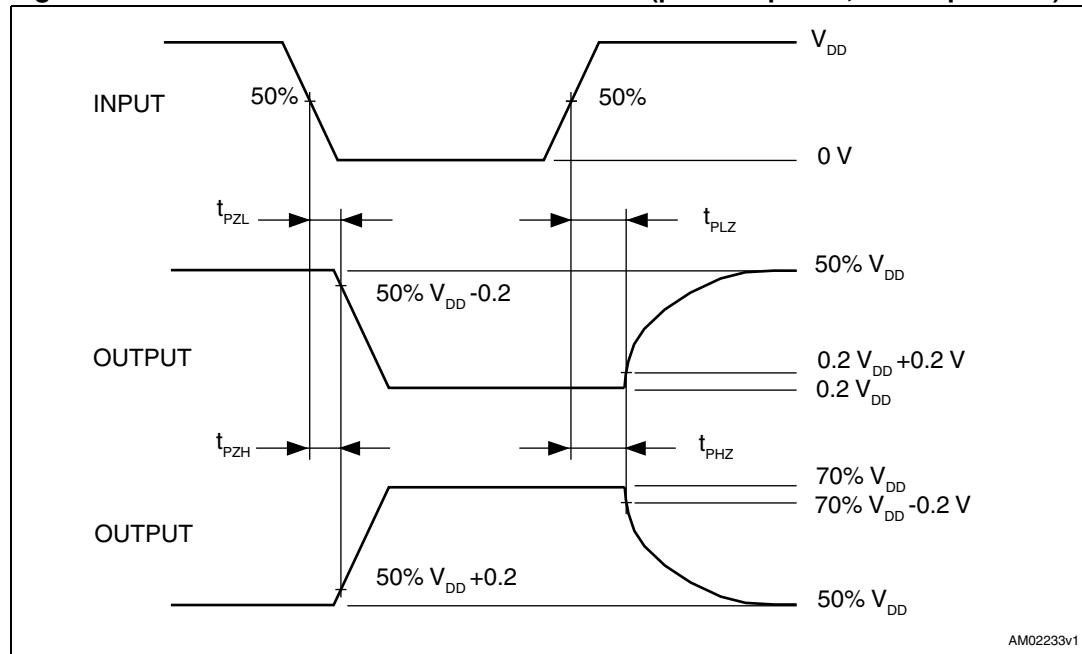
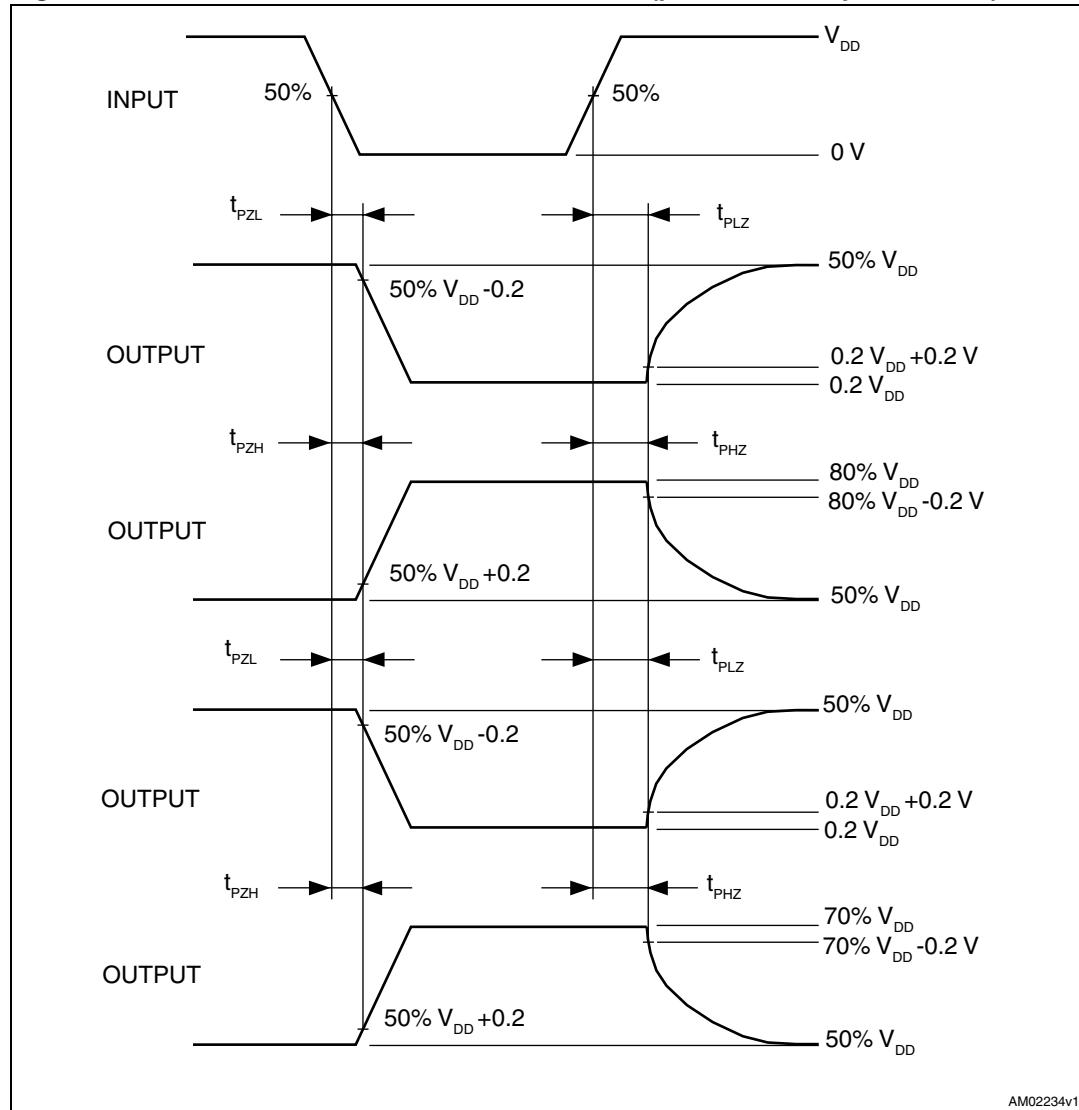
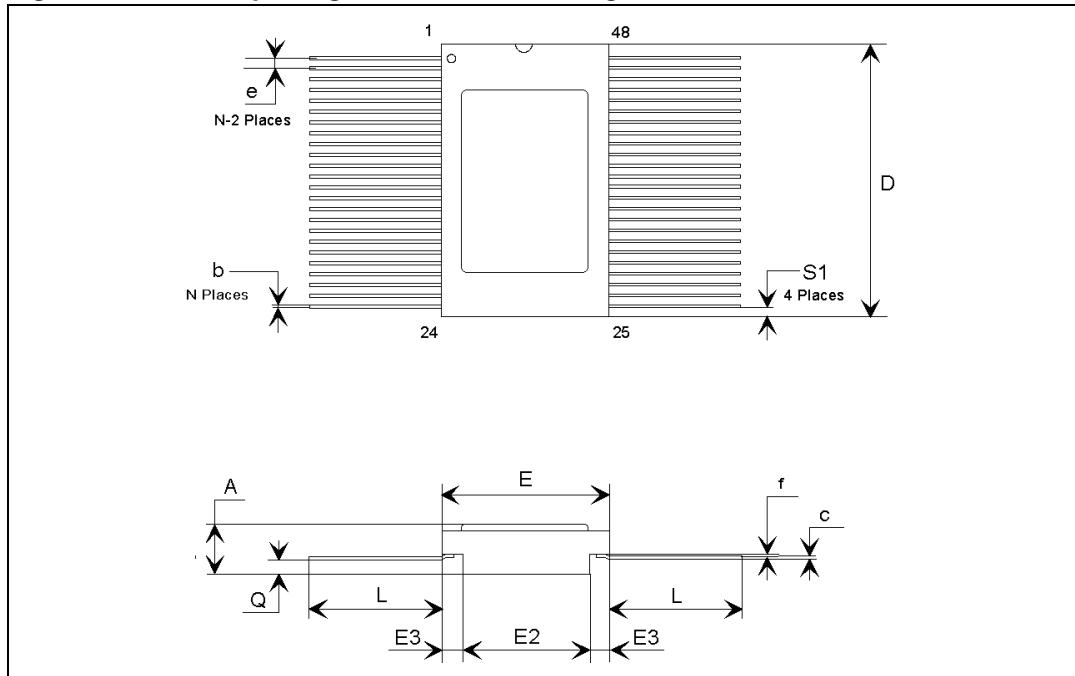
**Figure 5. Waveform 2: enable and disable times (port A = port B, 5 V operation)****Figure 6. Waveform 3: enable and disable times (port A = port B, 3.3 V operation)**

Figure 7. Waveform 4: enable and disable times (port A = 3.3 V, port B = 5 V)



## 6 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK is an ST trademark.

**Figure 8.** Flat-48 package mechanical drawing

Note: The upper metallic lid is not electrically connected to any pins, nor to the IC die inside the package. Connecting any unused pins or the metal lid to ground or to the power supply will not affect the electrical characteristics.

**Table 9.** Flat-48 mechanical data

| Dim | mm    |       |       | inch  |       |       |
|-----|-------|-------|-------|-------|-------|-------|
|     | Typ   | Min   | Max   | Typ   | Min   | Max   |
| A   | 2.47  | 2.18  | 2.72  | 0.097 | 0.086 | 0.107 |
| b   | 0.254 | 0.20  | 0.30  | 0.010 | 0.008 | 0.012 |
| c   | 0.15  | 0.12  | 0.18  | 0.006 | 0.005 | 0.007 |
| D   | 15.75 | 15.57 | 15.92 | 0.620 | 0.613 | 0.627 |
| E   | 9.65  | 9.52  | 9.78  | 0.380 | 0.375 | 0.385 |
| E2  | 6.35  | 6.22  | 6.48  | 0.250 | 0.245 | 0.255 |
| E3  | 1.65  | 1.52  | 1.78  | 0.065 | 0.060 | 0.070 |
| e   | 0.635 |       |       | 0.025 |       |       |
| f   | 0.20  |       |       | 0.008 |       |       |
| L   | 8.38  | 6.85  | 9.40  | 0.330 | 0.270 | 0.370 |
| Q   | 0.79  | 0.66  | 0.92  | 0.031 | 0.026 | 0.036 |
| S1  | 0.43  | 0.25  | 0.61  | 0.017 | 0.010 | 0.024 |

## 7 Ordering information

**Table 10. Order codes**

| Order code      | Description       | Temperature range | Package | Marking         | Packing               |
|-----------------|-------------------|-------------------|---------|-----------------|-----------------------|
| RHRAC164245K1   | Engineering model | -55 °C to +125 °C | Flat-48 | RHFAC164245K1   | Conductive strip pack |
| RHRAC164245K01V | QMLV-Flight       |                   |         | 5962R9858008VYC |                       |

## 8 Revision history

**Table 11. Document revision history**

| Date        | Revision | Changes   |
|-------------|----------|---|
| 23-Sep-2011 | 1        | Initial release.  |
| 06-Apr-2012 | 2        | Added Pin 4 description to <i>Table 3: Pin descriptions</i> . |

**Please Read Carefully:**

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

**UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.**

**UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.**

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2012 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

[www.st.com](http://www.st.com)